

N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (mA)
-20	5 @ $V_{GS} = 4.5$ V	200
	7 @ $V_{GS} = 2.5$ V	175
	9 @ $V_{GS} = 1.8$ V	150
	10 @ $V_{GS} = 1.5$ V	50

TrenchFET®
MOSFETs
1.5-V Rated

**ESD Protected
2000 V**
FEATURES

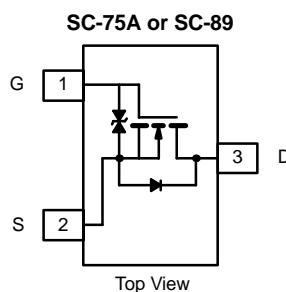
- Low-Side Switching
- Low On-Resistance: 5 Ω
- Low Threshold: 0.9 V (typ)
- Fast Swtiching Speed: 35 ns
- 1.8-V Operation
- Gate-Source ESD Protection

BENEFITS

- Ease in Driving Switches
- Low Offset (Error) Voltage
- Low-Voltage Operation
- High-Speed Circuits
- Low Battery Voltage Operation

APPLICATIONS

- Drivers: Relays, Solenoids, Lamps, Hammers, Displays, Memories
- Battery Operated Systems
- Power Supply Converter Circuits
- Load/Power Switching Cell Phones, Pagers


**SC-75A (SOT-416): Si1032R
SC-89 (SOT-490): Si1032X**
Marking Code: G
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Si1032R		Si1032X		Unit
		5 secs	Steady State	5 secs	Steady State	
Drain-Source Voltage	V_{DS}			20		
Gate-Source Voltage	V_{GS}			± 6		V
Continuous Drain Current ($T_J = 150^\circ\text{C}$) ^a	$I_A = 25^\circ\text{C}$	I_D	200	140	210	200
	$T_A = 85^\circ\text{C}$		110	100	150	140
Pulsed Drain Current ^a	I_{DM}	500		600		mA
Continuous Source Current (diode conduction) ^a	I_S	250	200	300	240	
Maximum Power Dissipation ^a for SC-75	$T_A = 25^\circ\text{C}$	P_D	280	250	340	300
	$T_A = 85^\circ\text{C}$		145	130	170	150
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150				°C
Gate-Source ESD Rating (HBM, Method 3015)	ESD	2000				V

Notes

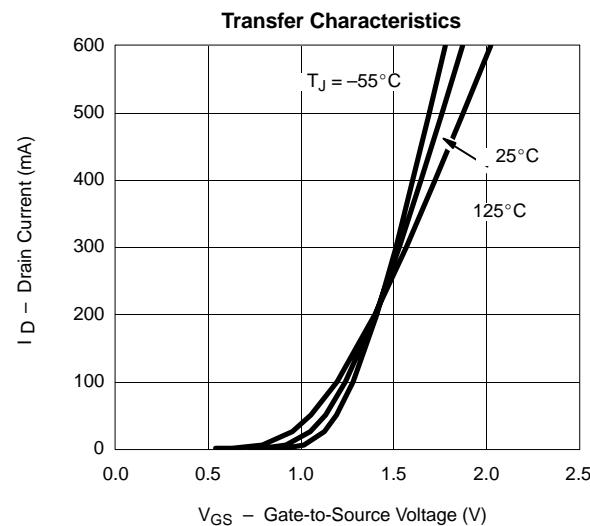
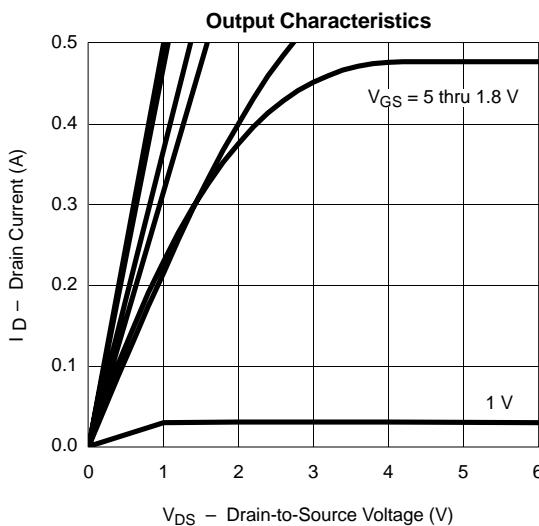
c. Surface Mounted on FR4 Board.

SPECIFICATIONS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.40	0.7	1.2	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 2.8 \text{ V}$		± 0.5	± 1.0	μA
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$		± 1.0	± 3.0	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$		1	500	nA
		$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 85^\circ\text{C}$			10	μA
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	250			mA
Drain-Source On-State Resistance ^a	$r_{DS(\text{on})}$	$V_{GS} = 4.5 \text{ V}, I_D = 200 \text{ mA}$			5	Ω
		$V_{GS} = 2.5 \text{ V}, I_D = 175 \text{ mA}$			7	
		$V_{GS} = 1.8 \text{ V}, I_D = 150 \text{ mA}$			9	
		$V_{GS} = 1.5 \text{ V}, I_D = 40 \text{ mA}$			10	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 10 \text{ V}, I_D = 200 \text{ mA}$		0.5		S
Diode Forward Voltage ^a	V_{SD}	$I_S = 150 \text{ mA}, V_{GS} = 0 \text{ V}$			1.2	V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 150 \text{ mA}$		750		pC
Gate-Source Charge	Q_{gs}			75		
Gate-Drain Charge	Q_{gd}			225		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 10 \text{ V}, R_L = 47 \Omega$ $I_D \approx 200 \text{ mA}, V_{GEN} = 4.5 \text{ V}, R_G = 10 \Omega$			50	ns
Rise Time	t_r				25	
Turn-Off Delay Time	$t_{d(\text{off})}$				50	
Fall Time	t_f				25	

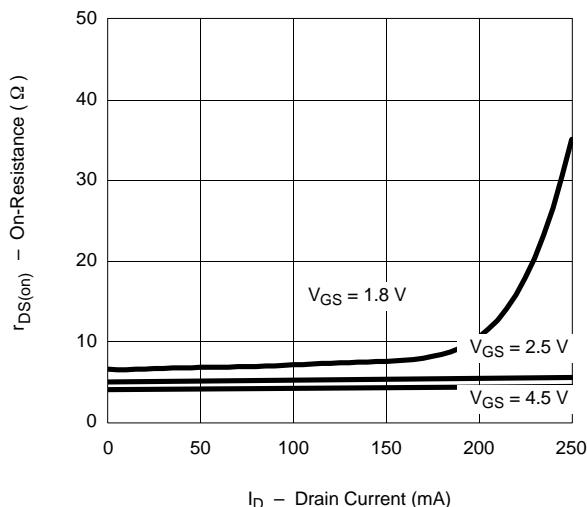
Notes

- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
 b. Guaranteed by design, not subject to production testing.

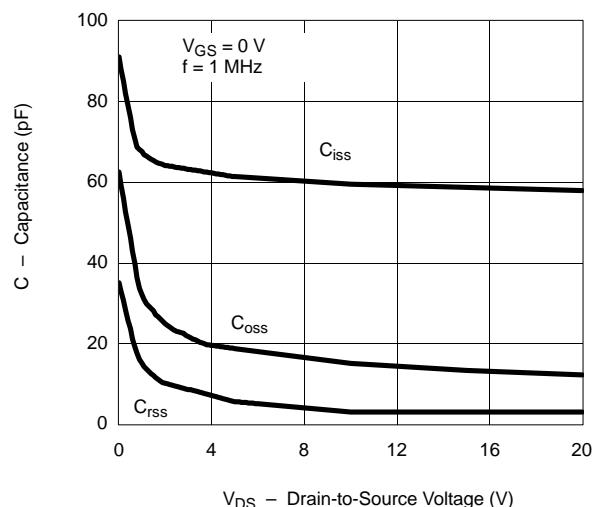
TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ UNLESS NOTED)

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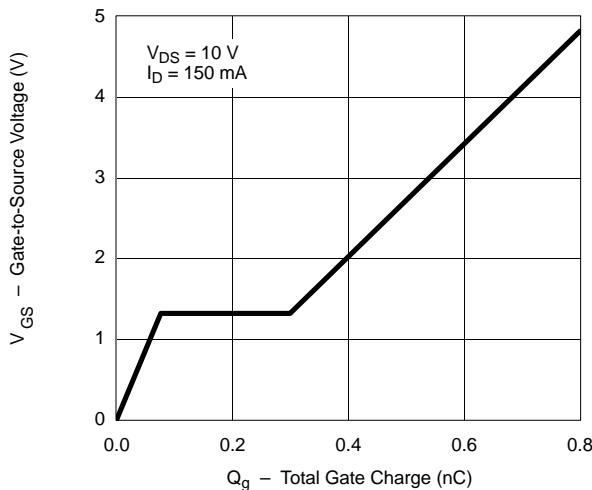
On-Resistance vs. Drain Current



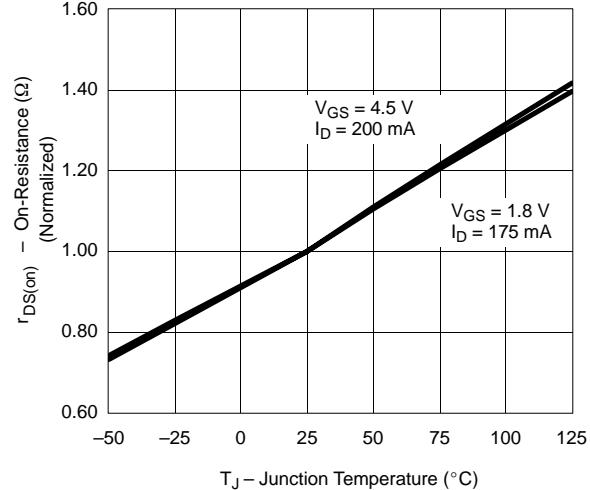
Capacitance



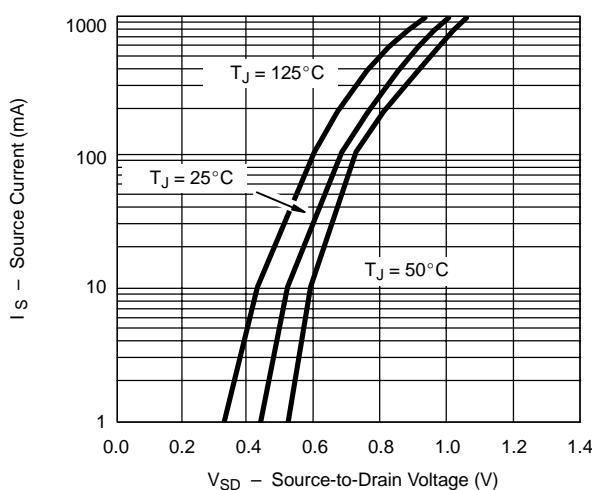
Gate Charge



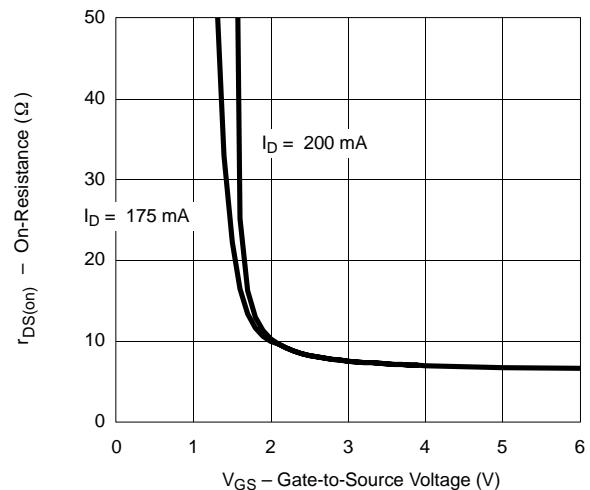
On-Resistance vs. Junction Temperature

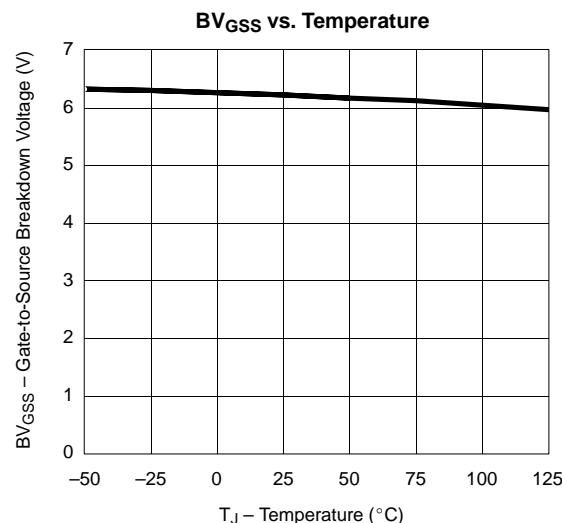
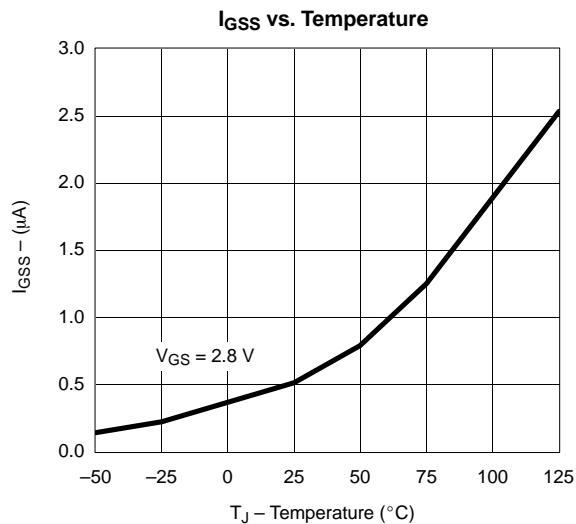
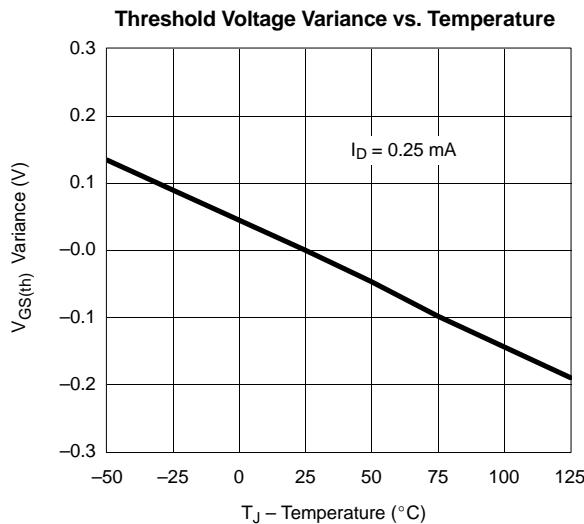


Source-Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage



TYPICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ UNLESS NOTED)**Normalized Thermal Transient Impedance, Junction-to-Ambient (SC-75A, Si1032R Only)**